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1 **Decrease in Thermal Conductivity in Polymeric P3HT Nanowires by**
2 **Size-Reduction induced by Crystal Orientation: New Approaches**
3 **towards Organic Thermal Transport Engineering.**

4 *Miguel Muñoz Rojo¹, Jaime Martín¹, Stéphane Grauby², Theodorian Borca-Tasciuc³, Stefan Dilhaire² and Marisol*
5 *Martin-Gonzalez¹.*

6 ¹ Instituto de Microelectrónica de Madrid, Calle de Isaac Newton, 8 28760 Tres Cantos, Madrid, Spain.

7 ² Univ. Bordeaux, LOMA, UMR 5798, 33405 Talence, France.

8 ³Rensselaer Polytechnique Institute, 110 8th St, Troy, NY 12180, United States.

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10
11 **Abstract**

12 To date, there is no experimental characterization of thermal conductivity of semiconductor
13 polymeric individual nanowires embedded in a matrix. This work reports on Scanning Thermal
14 Microscopy measurements in 3ω configuration to determine how the thermal conductivity of
15 individual nanowires made of a model conjugated polymer (P3HT) is modified when decreasing
16 their diameters. We observe a reduction of the thermal conductivity, from
17 $\lambda_{NW}=2.29\pm 0.15\text{W/K}\cdot\text{m}$ to $\lambda_{NW}=0.5\pm 0.24\text{W/K}\cdot\text{m}$, when the diameter of nanowires is reduced
18 from 350 nm to 120 nm, which correlates with the polymer crystal orientation measured by
19 WAXS. Through this work, the foundations for future polymer thermal transport engineering
20 are presented.

21 **Keywords:** 3ω -Scanning Thermal Microscopy, Organic P3HT Nanowires, size-confinement
22 effects, thermal conductivity reduction.

23 Nanostructuring is used to modify and control the transport properties of materials
24 due to confinement effects. For example, thermal conductivity reduction by size effects
25 has yielded to more efficient thermoelectric devices¹⁻². Among transport properties of
26 materials, especially challenging are measurements of the thermal conductivity, that
27 become even more difficult as the dimension of the material is reduced³. However, the
28 analysis of this physical property under nanoscale confinement is mandatory for a wide
29 variety of technological applications ranging from thermoelectrics to nanoscopic
30 thermal insulation, among others.

31 Generally, size effects on the thermal transport properties are dramatic for 1D
32 nanostructures due mainly to scattering processes, as heat propagation is confined to a
33 single spatial dimension. This has been theoretically predicted and experimentally
34 observed for inorganic nanowires (NWs)^{3,4}. However, little is known about how low
35 dimensionality affects the thermal transport properties in semiconducting polymer
36 materials, although severe changes are also expected, because nanoconfinement is well
37 known to induce structural and dynamical changes in nanoconfined polymers⁵.

38 Thereby, our aim is to clarify how the thermal conductivity of relevant semiconducting
39 polymer nanowires inside a matrix is altered by nanoconfinement.

40 Shen et al.⁶ measured for the first time the thermal conductivity of single ultra-
41 drawn polyethylene (PE) NWs and observed a dramatic increase of the thermal
42 conductivity of the NW as reducing diameter, which was correlated to the molecular
43 orientation and reduction of voids and defects. Likewise, Cao et al.⁷ reported the
44 enhancement of thermal conductivity of PE NWs. However, the measured NWs
45 consisted of collapsed bundles of NWs and thus, these measurement might be
46 influenced by the different environments experienced by the NWs-NWs at interior
47 positions of the bunch, from those at external positions, free NWs, etc. Therefore, to
48 understand the thermal behavior of NWs it is mandatory to study the thermal transport
49 of isolated NW in well controlled boundary conditions. For our study, we have selected
50 poly(3-hexylthiophene) (P3HT) as model semiconducting polymer, as P3HT is one of
51 the best characterized semiconducting polymers from a structural point of view⁸.
52 Furthermore, it has recently shown promising thermoelectric figures of merit at room
53 temperature, for which the characterization of the thermal conductivity was crucial to
54 calculate its efficiency⁹. Although little is known on the confinement effects on thermal
55 properties of P3HT, the few works reported on P3HT 2D thin films have shown
56 anisotropy of the thermal conductivity along the different spatial dimensions^{10 11}.
57 However, measurements of individual NW are extremely challenging due to the high
58 spatial resolution required and only very few techniques are able to do it with accuracy
59 ³.

60 In this work, a technique called 3ω -SthM and based on Scanning Probe Microscopy
61 (SPM)¹² has been used to carry out the first local measurements of thermal conductivity
62 on individual semiconducting polymer NWs. These measurements fill a gap in literature
63 and constitute a step toward the determination of how polymer materials behave at this
64 low scale.

65 On the one hand, the most typical technique that is able to measure the thermal
66 conductivity of single NWs is the microfabricated suspended device technique¹³.
67 Nevertheless, it is worth mentioning that this method, which measures only one NW at
68 the same time, requires many heavy processing steps and may leads to the oxidation of
69 the surface of the NWs, since they are not embedded in a matrix but in contact with air.

70 In addition, this technique measures the thermal conductivity of one NW isolated from
71 its matrix which can differ from the thermal conductivity of the NWs embedded in the
72 matrix, which constitutes the effective functioning device, because of the matrix/NWs
73 interactions¹⁴. On the other hand, there are several techniques that can carry out local
74 thermal characterization of arrays of nanowires embedded in a matrix, such as the time
75 domain thermoreflectance (TDTR)¹⁴, the photoacoustic technique¹⁵, photo-
76 thermoelectric technique¹⁶ or others based on micro-probe measurements¹⁷.
77 Nevertheless, the typical spatial resolution reached by these techniques are about 1 μm ,
78 which do not enable them to carry out thermal measurements on individual nanowires
79 but they give access to a mean value of the thermal conductivity of the whole sample.
80 The 3ω -SThM is a local technique that enables to carry out thermal images of individual
81 NWs with a 100nm typical thermal spatial resolution and a 10nm typical topographical
82 spatial resolution. This technique has the advantage to probe thermally a wide range of
83 individual NWs embedded in their matrix in short periods of time, ranging from 10 to
84 20 min depending on the signal generator frequency used^{18 19 20}. We obtain at the same
85 time a topographical image and a thermal image, enabling an easy localization of the
86 NWs. Determining at the same time if the pore is filled, what is the morphological
87 quality of the nanowires studied, etc. In addition from a single thermal image, we can
88 assess as many NWs measurements as the number of NWs in the image, leading to a
89 mean value and a standard deviation of the measured signal among nanowires²¹.

90 Thermal conductivity measurements are carried out with a 3ω -SThM (Scanning
91 Thermal Microscopy) working in contact mode (see supporting information S2). This
92 technique has been recently used to measure the thermal conductivity of inorganic NWs
93 of Si¹⁹, SiGe²¹ or Bi₂Te₃²⁰. Classically, 3ω -SThM measurements are performed using a
94 Wollastone probe²². However, the Wollastone probes face two main drawbacks: a
95 thermal spatial resolution around 1 μm comparable to TDTR, which makes it unsuitable
96 to probe individual NWs measurements at nanometric scale, and a low thermal cut-off
97 frequency which infers a low excitation frequency and hence a high acquisition time.
98 Pd/SiO₂ probes used in our measurements present a 100nm thermal spatial resolution
99 and a cut-off frequency ten times higher than the Wollastone one¹⁸. Thereby, in this
100 work the thermal conductivity of individual P3HT NW (with diameters of 120 nm, 220
101 nm and 350 nm) have been assessed by the Scanning Thermal Microscopy working in
102 3ω configuration while embedded in the alumina template.

103 The hexagonally ordered AAO templates with pores of 120, 220, and 350 nm in
104 diameter and 100 μm in length were synthesized by a two-step electrochemical
105 anodization of aluminum and subsequent chemical etching as reported in the literature
106 for templates with pore diameter in the 120-400 nm range^{23 24} (Supporting Information
107 Figure S1). For the fabrication of P3HT NWs, macroscopic pieces of commercial P3HT
108 from Aldrich Ltd. ($M_n=33\ 405$ g/mol, $M_w/M_n=1.50$, regionregularity = 96%) were
109 placed onto the surface of the AAO at 260 $^\circ\text{C}$ for 45 min in N_2 atmosphere²⁵. Then the
110 samples were taken out from the furnace, and quenched in ice-water, so that P3HT
111 rapidly solidified. The excess of P3HT at the AAO top surfaces was removed with a
112 razor blade and the surface polished with diamond paste (3 μm , Buehler MetaDi II).
113 SEM micrographs of the surface of infiltrated templates are shown in the supporting
114 information Figure S1a and S1b. Finally, the P3HT-infiltrated templates were annealed
115 at 125 $^\circ\text{C}$ for 30 min. A sketch of the samples is included in the Supporting Information
116 Figure S1c.

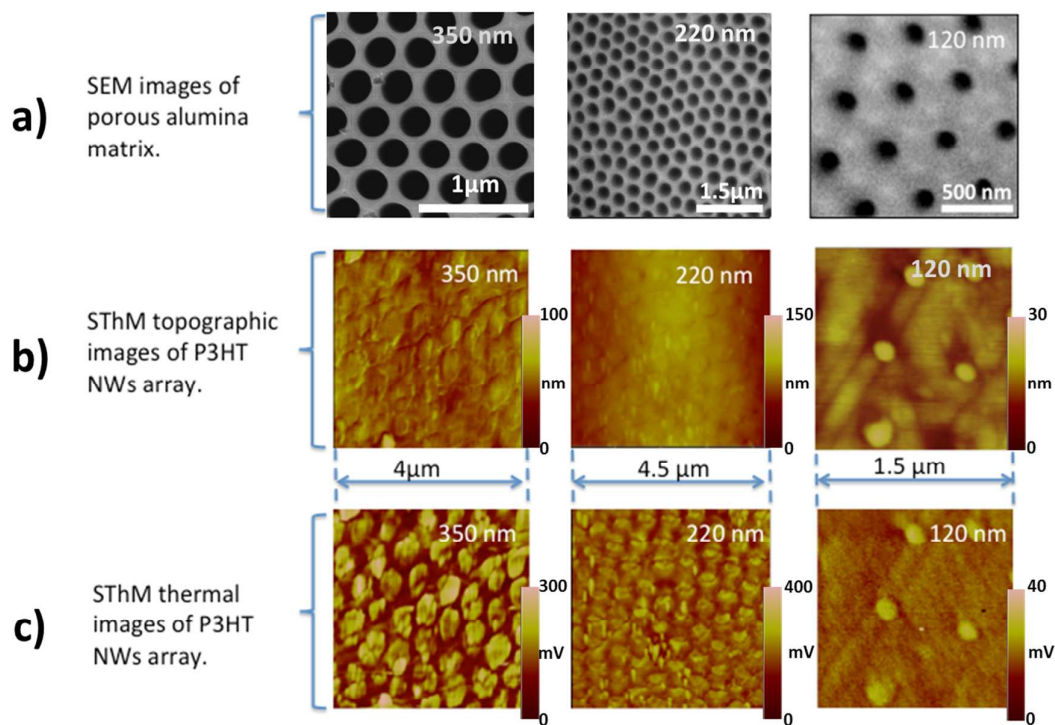
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118 Wide-angle X-ray scattering (WAXS) experiments in a geometry in which the
119 wave vector, Q , was parallel to the long axis of P3HT NWs were carried out in
120 reflection geometry using a Philips X'Pert diffractometer, (supporting information
121 Figure S3a). Moreover, WAXS experiments were also carried out in transmission
122 geometry with the X-ray beam traveling along the direction perpendicular to the
123 template surface using a Bruker AXS Nanostar X-ray scattering instrument (see
124 Supplementary Information Figure S3b), so that Q was nearly perpendicular to the long
125 axis of NWs. The underlying Al substrate was chemically etched from the AAO
126 templates for transmission measurements. The scattered X-rays were detected using a
127 two dimensional multiwire area detector (Bruker Hi-Star). The data were then converted
128 to one-dimensional scattering profiles by radial averaging along the azimuthal direction.
129 The sample to detector distance was 10 cm. Both instruments use Cu K_α radiation (1.54
130 \AA).

131 The 3ω -SThM was applied to measure P3HT NWs with different diameters
132 embedded in a porous alumina matrix. It is important mentioning that this experimental
133 technique not only allows measurements of the thermal resistance, R_{eq} , of individual
134 NW inside the matrix, but it also gives information of the R_{eq} of the whole composite²⁰.
135 This technique is based on a statistical data processing to determine the mean average of

136 the equivalent thermal resistance of the NWs and the whole composite, with its
 137 associated standard deviation.

138 Figure 1a shows Scanning Electron Microscopy (SEM) pictures of a top view of
 139 the un-filled porous alumina templates used to embed P3HT NW, as well as
 140 topographic (Figure 1b) and 3ω voltage ($(V_{3\omega})_{Tip}$) (Figure 1c) images of P3HT NWs
 141 with three different nanowire diameters size, 350nm, 220nm and 120nm, respectively.
 142 Additional SEM images of the P3HT NW embedded in the template are shown in the
 143 supporting information Figure S1a and S1b.



144

145 Figure 1.a) SEM pictures of the three different diameter size porous alumina matrix used to embedded
 146 P3HT NWs, b) topographic of the filled templates and c) $(V_{3\omega})_{Tip}$ or thermal images of P3HT NWs taken
 147 with a 3ω -SThM.

148

149 According to the $(V_{3\omega})_{Tip}$ thermal images of P3HT NWs, we can distinguish
 150 two areas in each of them: a high $V_{3\omega}$ signal area corresponding with the NWs locations
 151 and a low $V_{3\omega}$ signal area on the alumina. Then, the NW mean equivalent thermal
 152 resistances $(R_{eq})_{NW}$ for the three different diameters can be determined from the $V_{3\omega}$
 153 value measured on each NW. The results are shown in Table I. Let us underline that

154 each $(R_{eq})_{NW}$ value presented in this table has been obtained after measurements on
 155 20NWs (even for the 120nm NW sample for which we have used a thermal image
 156 larger than the one in Figure 1c). In this table it is also included the thermal exchange
 157 radius of the tip r_{ex} , whose value was specifically measured before each sample scan. It
 158 constitutes an important parameter to take into account when doing this analysis
 159 (Supporting Information S2). Indeed, not only does it influence the spatial resolution
 160 but it is also a key parameter in the estimation of the thermal conductivity through the
 161 evaluation of some of the thermal resistances involved in the total equivalent thermal
 162 resistance measured, as developed below¹⁸.

163 After the evaluation of the equivalent thermal resistance $(R_{eq})_{NW}$ on the NWs,
 164 one can determine the thermal conductivity of the NW. For that purpose, one must
 165 consider that the equivalent thermal resistance measured can generally be expressed as
 166 the addition of 4 thermal resistances in series, the tip to sample contact thermal
 167 resistance R_C , the constriction resistance R_{tip-NW} of the heat flux between the tip and the
 168 NW, the sample intrinsic thermal resistance R_{Com} , and the constriction resistance R_{NW-Sub}
 169 of the heat flux between the NW and the substrate on which the composite is deposited
 170²⁰. This is expressed by equation (1),

$$171 \quad (R_{eq})_{NW} = R_{Tip-NW} + R_C + R_{Com} + R_{NW-Sub} \quad (1)$$

172 On the one hand, the constriction resistance between the tip and the NW, R_{Tip-NW} ,
 173 is negligible as the thermal exchange surface is larger than the NW section, whose
 174 diameters vary from 350 nm to 120 nm. On the other hand, the heat flows through the
 175 whole composite and, given that the matrix is 100 μ m thick, the majority of the heat will
 176 not reach the substrate. Therefore, the constriction resistance between the NW and the
 177 substrate can be neglected.

178 Therefore, equation (1) is reduced to,

$$179 \quad (R_{eq})_{NW} = R_C + R_{Com} \quad (2)$$

180 In order to determine R_{Com} and subsequently λ_{Com} , it is now necessary to evaluate
 181 the thermal contact resistance, R_C . As developed by Lefevre et al.²², this resistance
 182 takes into account not only the solid-solid conduction between tip and sample, but also
 183 conduction through air and through the water meniscus, which constitutes the two other
 184 main heat transfer mechanisms under atmospheric conditions. It can be expressed as:

185 $1/R_C = G_c = G_S + G_A + G_W$ where G_S , G_A and G_W are respectively the conductance through
 186 solid-solid contact, through the air and through the water meniscus. The heat transfer
 187 mechanisms take place over a surface not defined by the contact-contact radius but by
 188 the thermal exchange radius r_{ex} , hence the necessity to calibrate this parameter¹⁸.

189 To evaluate R_C we measure the equivalent thermal resistance on the alumina
 190 matrix^{19, 20, 26, 27}. Indeed, in this case, the equivalent thermal resistance measured on the
 191 alumina is given by:

$$192 \quad (R_{eq})_{Alu} = R_c + R_{Tip-Alu} \quad (3)$$

193 where $R_{Tip-Alu}$ is the constriction resistance between the tip and the alumina matrix.
 194 Considering the matrix as a semi-infinite medium due to its dimensions in comparison
 195 with the thermal exchange radius r_{ex} , the constriction resistance can be expressed as²⁷

$$196 \quad R_{Tip-Alu} = \frac{1}{4\lambda_{Alu}r_{ex}} \text{ where } \lambda_{Alu} \text{ is the thermal conductivity of the alumina.}$$

197

198 As it was commented in ref.²⁰, the intrinsic thermal resistance R_{Com} does not
 199 correspond to the NW intrinsic thermal resistance, but to the local composite (alumina
 200 and NW) thermal resistance. Indeed, first, the thermal exchange surface is larger than
 201 the NW section; hence the hot tip heats not only the NW but the surrounding alumina
 202 matrix at the same time. In addition, the heat passing through the NW spreads towards
 203 the matrix since the NWs are in contact with the alumina and NWs and alumina are not
 204 expected to have much different thermal conductivities. R_{Com} can then be expressed as a
 205 constriction resistance on a semi-infinite effective medium,

$$206 \quad R_{Com} = \frac{1}{4\lambda_{Com}r_{ex}} \quad (4)$$

207 where λ_{Com} is the thermal conductivity of the composite calculated using the effective
 208 medium theory^{14 20}:

$$209 \quad \lambda_{Com} = x\lambda_{NW} + (1 - x)\lambda_{Alu} \quad (5)$$

210 where x is the areal packing density of the NW array, λ_{NW} and λ_{Alu} the intrinsic NW
 211 and the porous alumina matrix thermal conductivities, respectively. In ref.¹⁴, the
 212 authors study in detail the validity of two models to describe the thermal exchanges

213 between NWs and matrix, namely the effective medium and two-temperature models,
 214 when heating a sample made of NWs in a matrix using a modulated heat source. It is
 215 demonstrated that when the heat source is modulated at low frequencies ($f < 1\text{MHz}$),
 216 which is our case ($f = 1\text{kHz}$), the measured thermal conductivity approaches the thermal
 217 conductivity predicted by effective medium theory (equation (5)) with a thermal
 218 conductance of the matrix/NW interfaces $G_{\text{matrix/NW}} \rightarrow \infty$. Then, NWs and matrix are
 219 strongly coupled and the heat passing from the tip to the NW spreads to the surrounding
 220 matrix. We hence heat the whole composite medium over the thermal penetration
 221 length, which are typically several microns at this low frequency.

222 Table I. Areal packing density of the NW array and alumina, thermal exchange radius, equivalent thermal
 223 resistance and thermal conductivities of the composite, alumina matrix and intrinsic NWs for three
 224 different composites made of P3HT NWs array embedded in alumina matrix.

Nanowire diameters (nm)	Packing areal density of the NW array	Thermal exchange radius (nm)	$(R_{\text{eq}})_{\text{NW}}$ (K/W) $\times 10^6$	$(R_{\text{eq}})_{\text{Alumina}}$ (K/W) $\times 10^6$	Composite thermal conductivity (W/K·m)	Alumina matrix thermal conductivity (W/K·m)	NW thermal conductivity (W/Km)
350	0.55	175±10	4.36±0.11	4.63±0.03	1.89±0.08	1.38	2.29±0.15
220	0.25	175±10	4.49±0.06	4.34±0.02	1.18±0.06	1.38	0.70±0.12
120	0.08	81±5	6.48±0.03	6.36±0.02	1.31±0.02	1.38	0.50±0.24

225

226 Then, from the same $(V_{3\omega})_{\text{Tip}}$ image presented in Figure 1c we measured the
 227 $(V_{3\omega})_{\text{Tip}}$ signal on 20 locations on the alumina area for the three samples with porous
 228 size of 350nm, 220nm and 120nm. The thermal conductivity of the alumina matrix
 229 resulted to be $\lambda_{\text{Alu}} = 1.38\text{W/K}\cdot\text{m}$, see Table I, for the three templates. The thermal
 230 conductivity values show consistence since all the templates were prepared under the
 231 same conditions;^{23 25} the only difference is that the pores are widening by chemical
 232 etching and the porosity increase. With these values of the alumina the mean contact
 233 resistances are determined to be, $R_c = 3.60 \times 10^6$ K/W, $R_c = 3.31 \times 10^6$ K/W and
 234 $R_c = 4.12 \times 10^6$ K/W for the alumina with 350 nm, 220 nm and 120 nm in diameter pores,
 235 respectively. Often, the contact resistance is determined by calibration on a material of
 236 known thermal conductivity^{26 17}. It is then assumed that R_c does not change from
 237 sample to sample and when measuring other materials. Nevertheless, precautions need
 238 to be taken since this contact resistance may be very dependent on various parameters
 239 such as the surface roughness or the tip-to-sample contact geometry. In our case, when
 240 measuring $(R_{\text{eq}})_{\text{Alumina}}$ on the alumina part of the three samples, even if the tip is
 241 identical, we measure three different values (Table I), hence three different contact

242 resistances. We have previously proposed¹⁹ an original method to determine R_c
243 accurately: from a 3ω -SThM image, we deduce it from the equivalent thermal
244 resistances measured directly on the NWs. This method demands a sample with NWs
245 offering wide diameter dispersion, which is not the case here. But we have also shown¹⁹
246 that, determining the mean contact resistance subsequently from the equivalent thermal
247 resistance measured from the same 3ω -SThM image on the matrix of the same sample,
248 the estimated values obtained by both methods differ by less than 1%. Therefore, if it
249 does not seem appropriate to evaluate the contact resistance on a given sample and then
250 use the same value for other samples, measuring R_c on a part of a sample seems to give
251 a reliable value that can be used on another part of the same sample from a thermal
252 image obtained during the same scan under the same experimental conditions, in
253 particular with a contact force between tip and sample maintained constant by the AFM
254 feedback loop.

255 Afterwards, we take into account a possible $\pm 1\%$ relative error in the contact
256 resistance. This value, which is also consistent with the standard deviation evaluated on
257 $(R_{eq})_{Alumina}$ in Table I and from which we deduce R_c , can appear small in comparison
258 with classical mechanical contact resistance relative variations. Indeed, it only takes into
259 account the repeatability error which is reduced because, from one image, we do 20
260 measurements on the alumina part, reducing the standard deviation by almost 5. With
261 this $\pm 1\%$ possible error, the mean composite intrinsic thermal resistances, R_{Com} were
262 determined to be $R_{Com}=(0.760\pm 0.036)\times 10^6$ K/W, $R_{Com}=(1.180\pm 0.033)\times 10^6$ K/W and
263 $R_{Com}=(2.36\pm 0.041)\times 10^6$ K/W for the P3HT NWs with 350 nm, 220 nm and 120 nm
264 diameter, respectively.

265 From equation (2) and a low dispersion statistical study over 20 NWs, the local
266 thermal conductivity of the composites was deduced to be $\lambda_{Com} = 1.89 \pm 0.08$ W/mK,
267 $\lambda_{Com} = 1.18 \pm 0.06$ W/mK and $\lambda_{Com} = 1.31 \pm 0.02$ W/mK, for composites made of
268 P3HT NWs with 350nm, 220nm and 120nm diameters embedded in porous alumina
269 matrix, respectively. It is important mentioning that these values are extremely useful,
270 and relevant, as it constitutes the thermal conductivity values of possible functional
271 devices.

272 Finally, the intrinsic NWs thermal conductivity is calculated using equation (5).
273 In Table I the areal packing density of the NWs array evaluated from digital analysis of

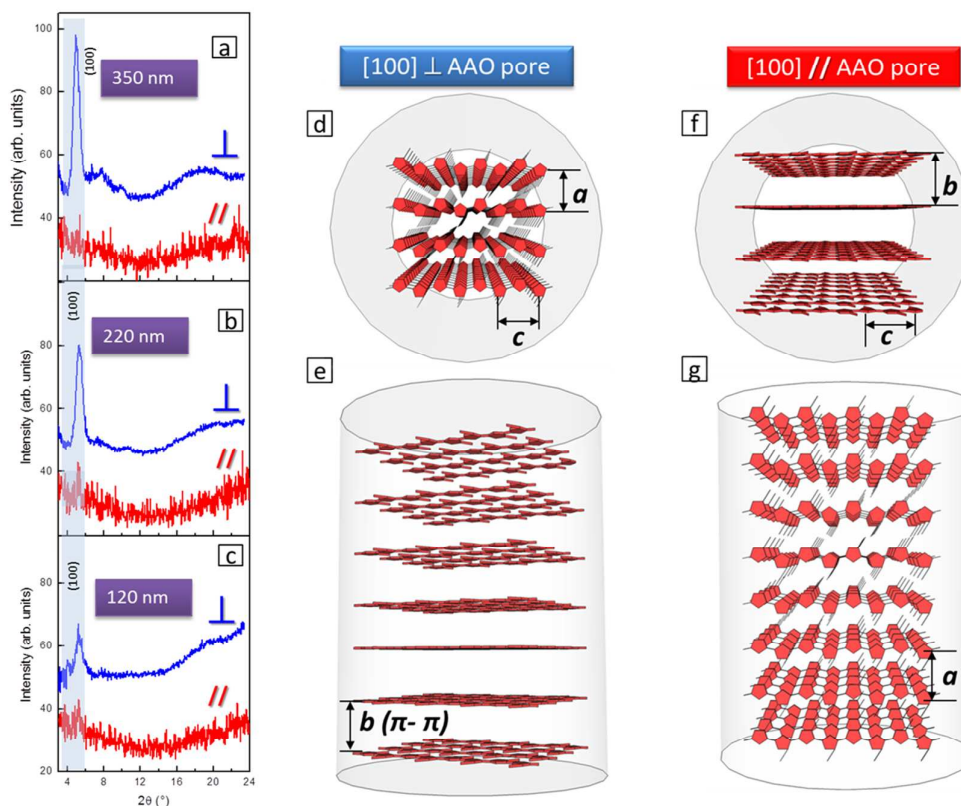
274 SEM pictures of the samples top views, the thermal conductivity of the three different
275 composites (considering it as a mixture of alumina and P3HT material), and the thermal
276 conductivities of individual P3HT NWs with 350 nm, 220 nm and 120 nm diameters is
277 shown. The validity of the effective medium theory to determine the thermal
278 conductivity of individual NWs have been checked with 3D simulations of the different
279 samples under the same experimental conditions as shown in Supplementary
280 Information (S5).

281 The results shown in Table I clearly evidence the reduction of the thermal
282 conductivity of individual P3HT NWs. For semicrystalline polymers, thermal
283 conductivity is known to depend on both the degree of crystallinity and the orientation
284 of their structural elements, i.e. molecules, aggregates, crystals, etc.²⁸ On the one hand,
285 crystals show intrinsically higher conductivity than amorphous regions, in such a way
286 that thermal conductivity of semicrystalline polymers is usually higher than that of
287 amorphous polymers. On the other hand, orientation phenomenon leads to a large
288 anisotropy in the thermal transport of semicrystalline polymers, that can be commonly
289 understood considering that molecular chains in the crystallites are aligned in a certain
290 direction, thus offering little thermal resistance along that direction. P3HT is known to
291 be a semicrystalline polymer and thus, the consideration above should be taken into
292 account when studying its thermal transport. Recently, Feng et al. have shown that
293 thermal conductivity of P3HT does not depend significantly on density, which can be
294 directly correlated to degree of crystallinity of the polymer²⁹. They observed an
295 increase of only 12 % of the thermal conductivity between P3HT films having density
296 values around 1 g/ml (which according to Ro et al. corresponds to completely
297 amorphous P3HT³⁰) and those having values around 1.6 g/ml (highly crystalline
298 P3HT). This low crystallinity dependence of the thermal conductivity in polymers
299 having medium degrees of crystallinity, like P3HT (the degree of crystallinity of bulk
300 P3HT has been proposed to be somewhat below 50 %³¹), has been suggested to be a
301 consequence of the difference in elastic properties between amorphous and crystalline
302 regions, which causes a high thermal boundary resistance at the many interfaces
303 between amorphous regions and crystals²⁸.

304 In contrast, orientation phenomena are likely to modify strongly the thermal
305 conductivity of semicrystalline polymers and to induce a large anisotropy as a function
306 of the crystallographic directions. Piraux *et al.*³² observed that the thermal conductivity

307 of oriented polyacetylene films (another semicrystalline conjugated polymer) were 15-
308 60 times higher than that of the non-oriented polyacetylene. Kiliam *et al.*³³ reported that
309 the thermal diffusivity in stretched polyethylene was 50 times higher along the drawing
310 direction than along the perpendicular direction. Moreover, this observation contrasts to
311 the behavior of amorphous polyethylene, for which only a 2 fold increase was
312 measured. This fact points out the special relevance of crystal orientation phenomena
313 when dealing with semicrystalline polymers. Likewise, Feng *et al.* has recently reported
314 a strong anisotropic thermal transport in P3HT films along the 3 spatial dimensions¹⁰.

315 2D-nanoconfinement, like the one imposed by the cylindrical nanopores of AAO
316 templates, frequently induces a preferential orientation of the confined polymer crystals
317^{34 35}. Thus, to elucidate whether changes in the orientation of P3HT crystals in the
318 NWs may be at the origin of the reduction of their thermal conductivities, WAXS
319 measurements were carried out for two different spatial directions, i.e. directions
320 parallel and perpendicular to NW long axis. Note that, 2D patterns were collected in the
321 direction perpendicular to NWs and then converted to one-dimensional scattering
322 profiles by radial averaging along the azimuthal angle. All the samples showed
323 diffraction rings in the perpendicular direction (not shown).



324

325 Figure 2. WAXS diffractograms of ensembles of P3HT NWs in which the wave vector, Q , was
 326 perpendicular to nanowires (lower red line with // symbol) and parallel to nanowires (upper blue line with
 327 ⊥ symbol) for (a) 350 nm, (b) 250 nm and (c) 120 nm NW arrays. Schematic illustrations of the 3
 328 possible ideal spatial orientations of the P3HT crystallite within nanopores from up and transversal
 329 perspectives: (d and e) top and side view of the b axis of the crystal cell (π - π stacking direction) parallel
 330 to NW long axis which also corresponds to 100 perpendicular, and (f and g) top and side view of the a
 331 axis of the crystal cell ([100] growth direction) parallel to NW long axis.

332

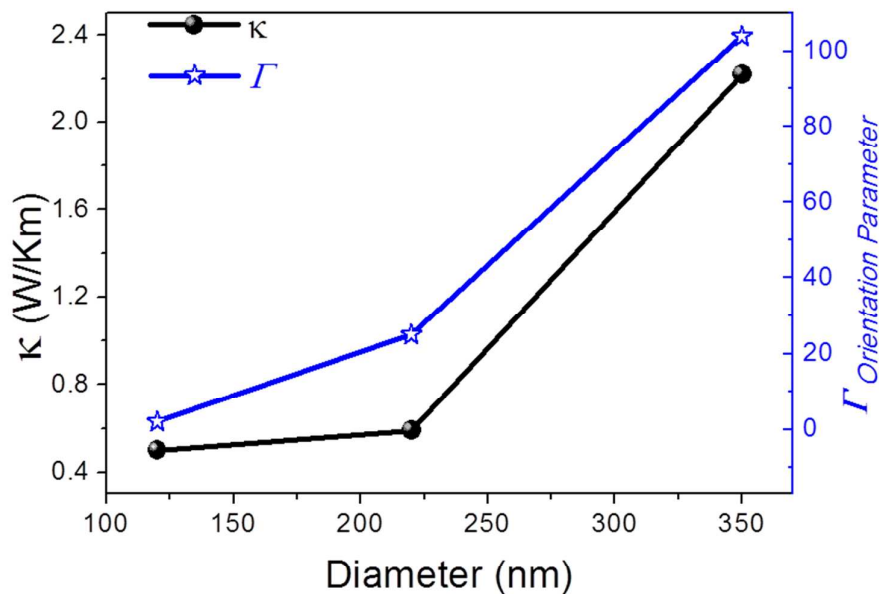
333 In the experimental geometry in which the wave vector, Q , was perpendicular to
 334 NW long axis, the three samples (P3HT NWs of 350, 220 and 120 nm diameters)
 335 showed a diffraction maximum at $2\theta = 5.2^\circ$ corresponding to the stacking of the main
 336 chain/side-chain layered structure of the P3HT crystal along the a axis^{36 37} (Figure 2a,
 337 2b and 2c). In general, in the three samples, crystals were preferentially oriented lying
 338 with their [100] crystallographic direction perpendicular to NW long axis and thus, the
 339 [010] direction (the π - π stacking direction) or the [001] directions lay preferentially
 340 parallel to the NW axis (ideally represented in Figure 2d,e). The most plausible
 341 orientation is the one in which crystals lay the π - π stacking direction parallel to
 342 nanowire long axis, as that orientation is the one fulfilling the Bridgeman mechanism³⁸

343 ^{39 40} for orientations guided by kinetic aspects, as it has been usually observed in
344 commodity polymers confined in nanopores ^{39 40}. Such mechanism dictates that the
345 crystallographic direction with the fastest growth rate aligns parallel to the NW long
346 axis. For P3HT crystal, π - π stacking direction is known to be the fastest growth
347 direction^{36 41}, thus is expected to be parallel to NW long axis. The diffraction peak
348 shows a decrease in intensity and a broadening upon reduction of the diameter of the
349 nanowires from 350 to 120 nm. There are three main reasons for this: a) the porosity %
350 of the alumina template is lower in the 120 nm (8%) than in 220 nm (25%) than in 350
351 nm (55%), so the amount of diffracting P3HT is the lowest in 120 nm. B) The crystal
352 size is smaller while reducing the wire diameter, so the diffraction peaks become
353 broader. And, c) some of the P3HT crystals may tilt under confinement.

354 The (100) diffraction for Q parallel to NWs long axis was absent in 350 nm
355 nanowires, while weak (100) peaks become to be visible for 250 and 120 nm samples,
356 being more intense in 120 nm nanowires. This means that as nanowire diameter is
357 reduced, more and more crystals are tilt toward the [100] direction parallel to NWs axis.
358 Note that in crystals with the [100] direction parallel to NWs axis, the [010] direction is
359 almost perpendicular to the AAO pore walls. Since the [010] direction is that of the
360 fastest growth, P3HT crystallites would tend to grow along that direction, but they
361 impinge on the pore walls and die. This would lead these crystals to be considerably
362 small, which would generate non-well-developed diffraction peaks when measuring in
363 the geometry where Q is parallel to nanowire axis. This new configuration of the chain
364 is ideally represented in Figure 2f,g).

365 To perform a semiquantitative analysis of the crystal orientation of P3HT NWs,
366 an orientation parameter Γ , defined as $\Gamma = \gamma_{\perp} / 1.18\gamma_{\parallel}$, being γ_{\perp} and γ_{\parallel} the areas of the
367 (100) peaks in direction perpendicular and parallel to the NW axis, respectively. The
368 coefficient 1.18 was extracted from the ratio $\gamma_{\perp} / \gamma_{\parallel}$ of the bulk P3HT powder
369 (Supporting information Figure S3), considering the fact that crystals must be
370 isotropically oriented in that sample and thus Γ must be equal to unity (the P3HT was
371 powdered in an agate mortar). In this way, Γ is closely related to the preferential
372 orientation of the (100) planes in the NWs. Since $\Gamma > 1$ for the three samples, crystals
373 laid with their [100] crystallographic direction preferentially perpendicular to the NW
374 axis and thus, [010] and/or [001] directions were preferentially parallel to the NW axis
375 (Figure 2e and 2f). As can be observed in Figure 3, Γ decreased as the pore diameter

376 decreases, suggesting the presence of more and more crystals with [100] parallel to
377 NWs, as ideally represented in Figure 2d. Note that although we cannot assure whether
378 the extended polymer chain direction (c axis) or the π - π stacking direction (b axis) are
379 parallel to NW long axis, both of them are expected to present little thermal resistance
380 in analogous way to what occurs with electronic transport (the main electronic
381 conduction in P3HT takes place along the thiophenic backbone and along the π - π
382 stacking direction). This is because strong conjugated covalent bonds along the chain
383 direction ([001] direction) and the compact π - π stacking (along the [010] direction)
384 would facilitate the phonon transport along those crystallographic directions. In
385 contrast, the [100] crystallographic direction is the one along which the alternation of
386 layers of thiophenic chains and aliphatic chains take place. Thereby, insulating aliphatic
387 regions separate the more conductive thiophenic layers, which may introduce additional
388 thermal boundary resistances in the crystal structure along that direction. Furthermore,
389 many authors maintain that medium size alkyl side chains, such as the hexyl groups of
390 P3HT, keep disordered after the crystallization of thiophenic layers⁴², which would
391 increase further the thermal barriers at those regions. Therefore, we attribute the
392 reduction of the thermal conductivity in P3HT NWs as reducing the diameter to the
393 decreasing presence of crystals oriented with [010] crystallographic direction parallel to
394 NWs. These results are qualitatively in accordance with the anisotropy of the thermal
395 conductivity of oriented P3HT films found by Feng et al.¹⁰, as well as by other authors
396 for non-conjugated polymers confined in nanopores⁷.



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398 Figure 3. Plot of the thermal conductivity (black spheres) the orientation parameter, Γ , (blue stars) of
 399 P3HT NWs as a function of the NW diameter. $\Gamma = \gamma_{\perp} / 1.18\gamma_{\parallel}$, being γ_{\perp} and γ_{\parallel} the areas of the (100)
 400 peaks in direction perpendicular and parallel to the NWs axis, respectively. The coefficient 1.18 is
 401 extracted from the ratio $\gamma_{\perp} / \gamma_{\parallel}$ of the bulk P3HT.

402 Figure 3 shows that varying the diameter of the nanowire will lead to a reduction in
 403 its thermal conductivity. These nanowires could be used potentially in different
 404 application in thermal transport engineering because of choosing a particular diameter
 405 the changes in its thermal conductivity are appreciable. Therefore, the heat flow across a
 406 device could be controlled with a certain magnitude by selecting the appropriate P3HT
 407 diameter nanowire.

408 In summary, this work presents a correlation of the thermal conductivity of 1D
 409 semicrystalline polymer nanostructures with the orientation of their crystals. This
 410 involves a better understanding of the effects of size confinement in polymers and its
 411 correlation with their thermal transport. Particularly, P3HT nanowires of three different
 412 diameters were studied and a drastic reduction of their thermal conductivity was
 413 observed as reducing diameter. Such reduction is proposed to be consequence of an
 414 increasing presence of crystals oriented laying the [100] direction parallel to nanowire
 415 long axis. This analysis evidences the huge potential of nanoscale crystal engineering to
 416 modulate thermal transport along the NWs, which may establish the foundations of
 417 future nanostructured heat thermal transport engineering for different applications

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422 **Acknowledgments**

423 Authors thank A. Nogales for WAXS measurements. M. M. R wants to
424 acknowledge JAE-PreDoc for its financial support. And ERC 2008 Starting Grant
425 “Nano- TEC” number 240497 and Nanotherm Consolider CSD-2010-00044 projects are
426 acknowledged for financial support.

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